

May 2001

FQPF50N06L

60V LOGIC N-Channel MOSFET

General Description

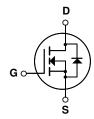
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as automotive, DC/ DC converters, and high efficiency switching for power management in portable and battery operated products.

Features

- 32.6A, 60V, $R_{DS(on)}$ = 0.021 Ω @V_{GS} = 10 V Low gate charge (typical 24.5 nC)
- Low Crss (typical 90 pF)
- Fast switching
- · 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQPF50N06L	Units
V _{DSS}	Drain-Source Voltage		60	V
I _D	Drain Current - Continuous (T _C = 25°	°C)	32.6	Α
	- Continuous (T _C = 100°C)		23.1	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	130	А
V_{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	1000	mJ
I _{AR}	Avalanche Current	(Note 1)	32.6	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	4.7	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P _D	Power Dissipation (T _C = 25°C)		47	W
	- Derate above 25°C		0.31	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		3.22	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			٧
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to 25°C		0.06		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 48 V, T _C = 150°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics				1	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1.0		2.5	V
R _{DS(on)}	Static Drain-Source	V _{GS} = 10 V, I _D = 16.3 A		0.017	0.021	_
20(011)	On-Resistance	$V_{GS} = 5 \text{ V}, I_D = 16.3 \text{ A}$		0.020	0.025	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 25 \text{ V}, I_D = 16.3 \text{ A}$ (Note 4)		35		S
	ic Characteristics	T	I	1050	1000	
Ciss	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		1250	1630	pF
C _{oss}	Output Capacitance Reverse Transfer Capacitance	f = 1.0 MHz		445 90	580 120	pF pF
Orss	neverse transfer Capacitatice			90	120	рг
Switchi	ng Characteristics				Ī	
t _{d(on)}	Turn-On Delay Time	V _{DD} = 30 V, I _D = 26.2 A,		20	50	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		380	770	ns
$t_{d(off)}$	Turn-Off Delay Time			80	170	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		145	300	ns
Q_g	Total Gate Charge	$V_{DS} = 48 \text{ V}, I_D = 52.4 \text{ A},$		24.5	32	nC
Q_{gs}	Gate-Source Charge	$V_{GS} = 5 V$		6		nC
Q_{gd}	Gate-Drain Charge	(Note 4, 5)		14.5		nC
	Source Diode Characteristics a		T	1		
l _S	Maximum Continuous Drain-Source Diode Forward Current				32.6	A
I _{SM}	Maximum Pulsed Drain-Source Diode F				130	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 32.6 \text{ A}$			1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 52.4 \text{ A},$		65		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		125		nC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 1. Le 1.1mH, $I_{AS} = 32.6A$, $V_{DD} = 25V$, $R_G = 25 \Omega$, Starting $T_J = 25^{\circ}C$ 3. $I_{SD} \leq 52.4A$, di/dt $\leq 300A/\mu_S$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^{\circ}C$ 4. Pulse Test : Pulse width $\leq 300\mu_S$, Duty cycle $\leq 2\%$ 5. Essentially independent of operating temperature

Typical Characteristics

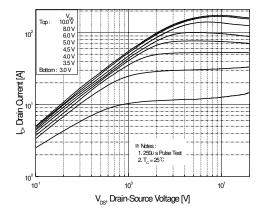


Figure 1. On-Region Characteristics

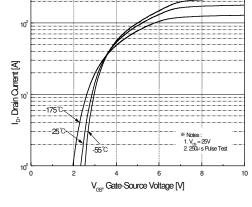


Figure 2. Transfer Characteristics

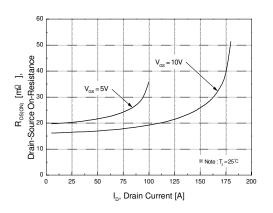


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

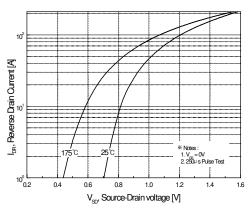


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

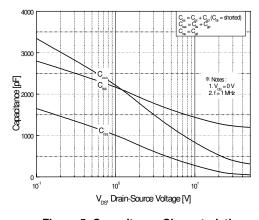


Figure 5. Capacitance Characteristics

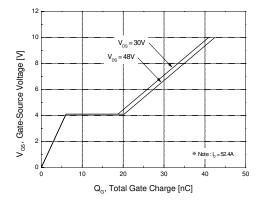


Figure 6. Gate Charge Characteristics

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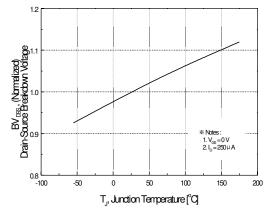


Figure 7. Breakdown Voltage Variation vs. Temperature

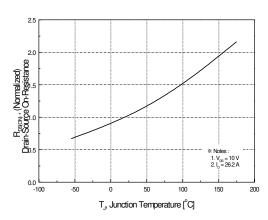


Figure 8. On-Resistance Variation vs. Temperature

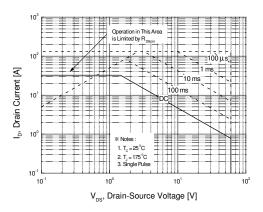


Figure 9. Maximum Safe Operating Area

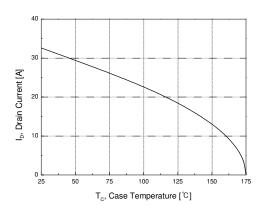


Figure 10. Maximum Drain Current vs. Case Temperature

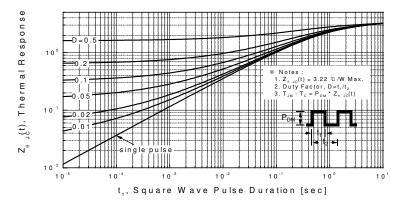
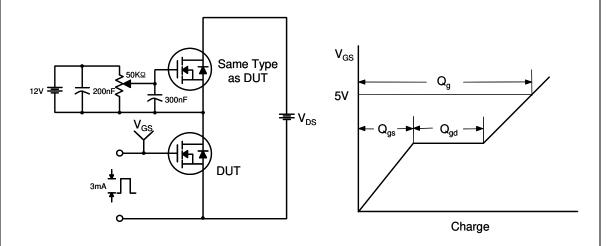


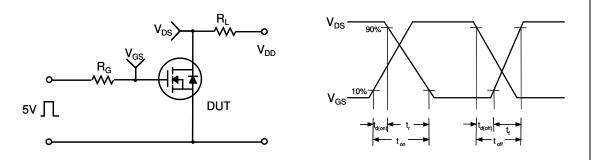
Figure 11. Transient Thermal Response Curve

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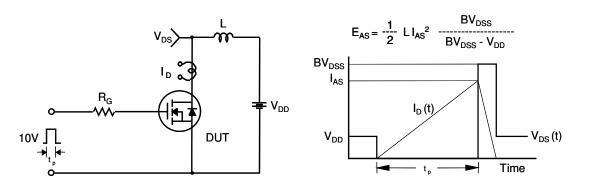
Gate Charge Test Circuit & Waveform



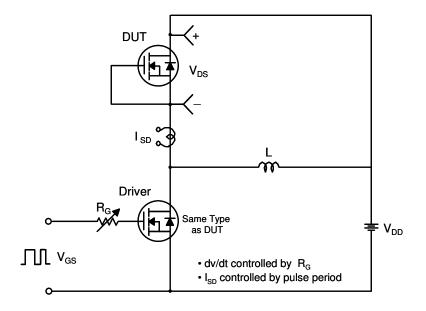
Resistive Switching Test Circuit & Waveforms

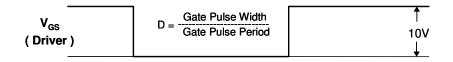


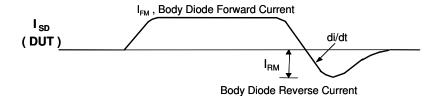
Unclamped Inductive Switching Test Circuit & Waveforms

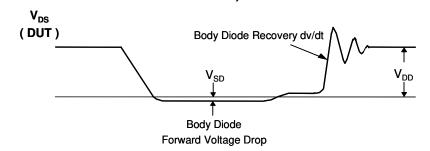


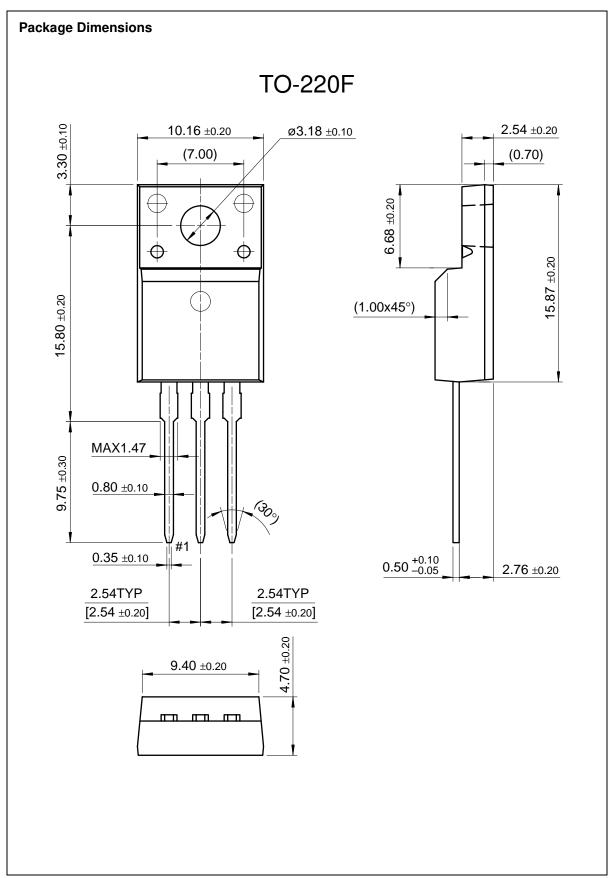
Peak Diode Recovery dv/dt Test Circuit & Waveforms











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